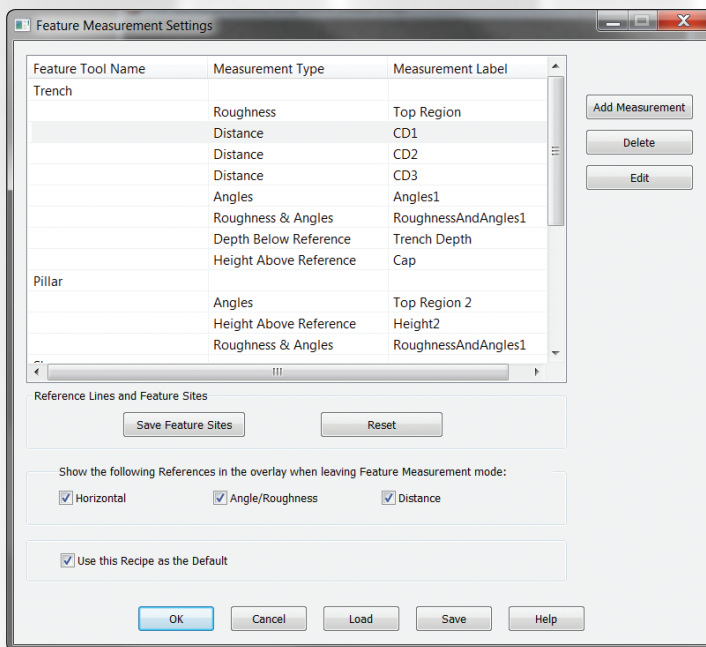


# Automated Measurement for Semiconductor Features

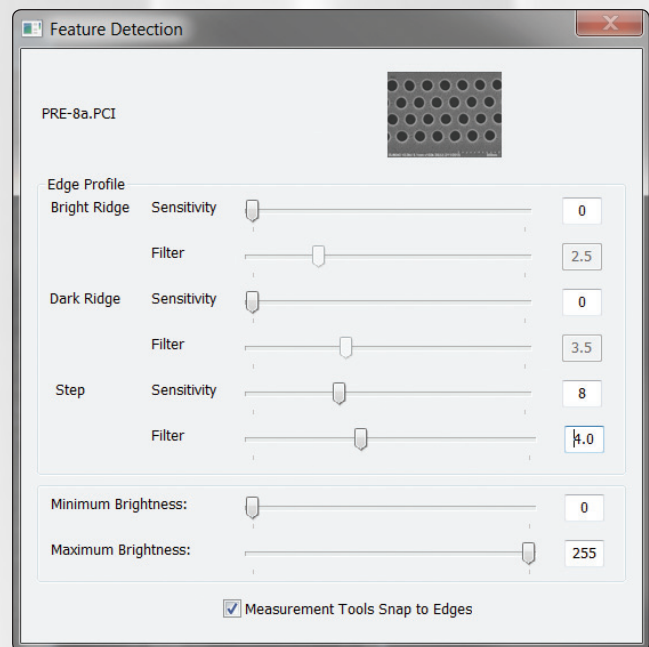
Just Click... and That's it.

## 2 Levels of 'Single Click' Automation:

1. Fully Characterize a Feature with a Single Click
2. Characterize a Multiple Feature Image with a Single Click Using PCI-AM Recipes



Create and Save Recipes for Measurement Types, Locations and Labels. Load the Recipe for Similar Images.



Our Edge Detection Techniques (3) allow you to work with more types of images and more types of features.

## PCI-AM Benefits:

- Save Time
- Increase Measurement Consistency
- Generate Reports Easily with Images and Data
- Increase Measurement Accuracy
- Export Data Easily Into CSV File



## QUARTZ IMAGING CORPORATION

SPECIALIZED SOLUTIONS FOR ELECTRONIC DEVICE LABS & ANALYSIS

6190 Agronomy Rd, Suite 406 Vancouver, BC Canada V6T 1Z3

Phone: +1-604-488-3911 • Fax: +1-604-488-3922 • [inform2@quartzimaging.com](mailto:inform2@quartzimaging.com) • [www.quartzimaging.com](http://www.quartzimaging.com)

**FOR A FASTER  
SMARTER LAB**

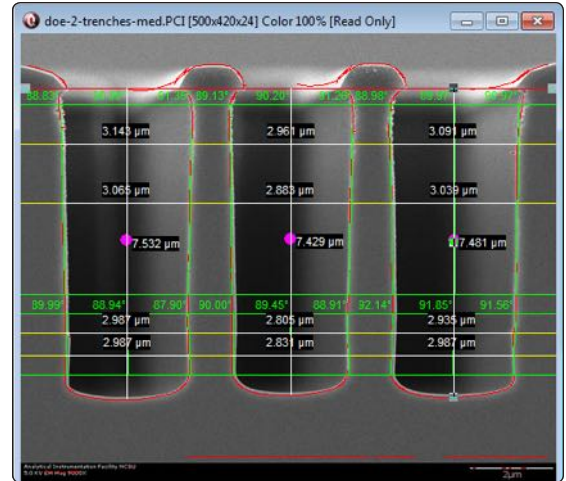
Copyright © 2016 Quartz Imaging Corporation. All rights reserved. Quartz PCI is a trademark of Quartz Imaging Corporation. All other trademarks and registered trademarks are the property of their respective holders. In keeping with our policy of ongoing research and development, specifications are subject to change without notice.

# Automated Measurement for Semiconductor Features

## Types of Automated Measurements

### Trenches (Spaces) and Pillars (Lines)

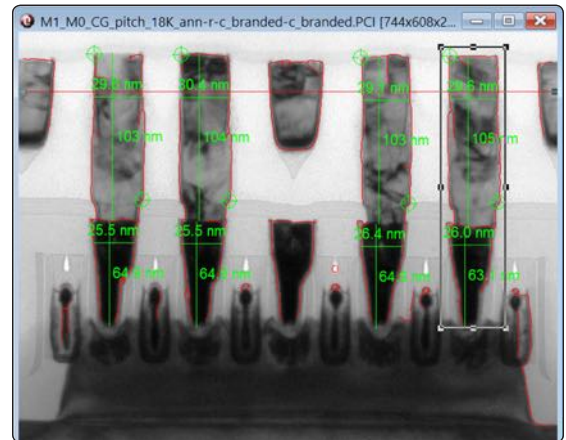
- CD Width
- Angles – Sidewall and Center
  - Multiple Regions in Feature
- Line Edge Roughness
- Line Width Roughness **NEW**
- Distances Below and Above Reference Line
- Averages of the Above Measurements



Trench Measurements

### Macro Cell **NEW**

- Multiple Measurements in Complex Features with a Single Click



Macro Cell

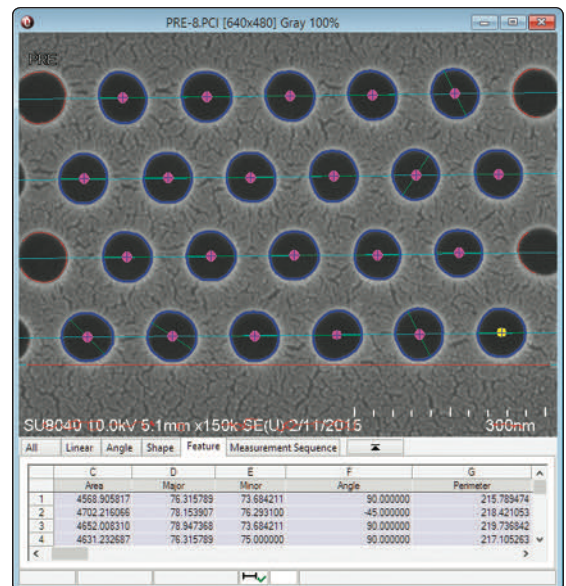
### Shapes

- Area and Perimeter
- Major and Minor Axes
- Ideal Shape Deviation
- Collinearity
- Aspect Ratio
- Tilt

### Other New Valuable PCI-AM Features

- “Point and Shoot” Horizontal and Vertical Measurement Tools Utilize Edges **NEW**
- Regular PCI Measurement Tools will “Snap” to the Edges in PCI-AM **NEW**

We Can Custom Develop any Specific Measurements You Require.



Shape Measurements